

Image

AF/2829



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE  
NOTICE OF APPEAL FROM THE PRIMARY EXAMINER  
TO THE BOARD OF PATENT APPEALS AND INTERFERENCES

In re application of:

KAMBIZ HAYAT-DAWOODI

Serial No.: 09/873,057 (TI-29619)

Filed: June 2, 2001

For: INTEGRATED CIRCUIT LEADFRAMES PATTERNED FOR  
MEASURING THE ACCURATE AMPLITUDE OF CHANGING CURRENTS

Group Art Unit: 2829

Examiner Russell Marc Kobert

Director of the United States  
Patent and Trademark Office  
P.O. Box 1450  
Alexandria, VA 22313-1450

02/26/2004 JADD01 00000078 200668 09873057  
01 FC:1401 330.00 DA

Sir:

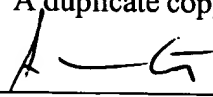
Applicant hereby appeals to the Board of Appeals from the decision dated December 21, 2003 of the Primary Examiner finally rejecting claims 1 to 5 and 7 to 9, all of the rejected claims.

The item(s) checked below are appropriate:

1. ☐ An extension of time to respond to the final rejection  
☐ was granted on  
☐ is requested for \_\_\_\_\_ month(s).
2. ☐ A timely response to the final rejection has been filed, as provided in 841 O.G. 1411.
3. ☒ Fee \$330.00:  
☐ Not required (*Fee paid in prior appeal*)  
☒ The Commissioner is hereby authorized to charge any fees which may be required, or credit any overpayment to Account No. 20-0668. A duplicate copy of this sheet is enclosed.

Signature [Rule 191(b)]

Post Office Address  
(to which correspondence is to be sent)

  
Jay M. Cantor, Reg. No. 19906  
Texas Instruments Incorporated  
P. O. Box 655474, M/S 3999  
Dallas, TX 75265  
(301) 424-0355



CERTIFICATE OF MAILING UNDER 37 C.F.R. § 1.8 (a)

I certify that the attached document as listed below is being deposited with the United States Postal Services as First Class Mail in an envelope addressed to the Director of the United States Patent and Trademark Office, P.O. Box 1450, Alexandria, VA 22313-1450 on the date indicated below.

Notice of Appeal

2-23-04

Jay M. Cantor

In re application of

KAMBIZ HAYAT-DAWOODI

Serial No.: 09/873,057 (TI-29619)

Filed: June 2, 2001

For: INTEGRATED CIRCUIT LEADFRAMES PATTERNED FOR  
MEASURING THE ACCURATE AMPLITUDE OF CHANGING CURRENTS